2-Bit 20 Mb/s Dual-Supply Level Translator

The NLSX4402 is a 2-bit configurable dual-supply bidirectional auto sensing translator that does not require a directional control pin. The V_{CC} I/O and V_L I/O ports are designed to track two different power supply rails, V_{CC} and V_L respectively. Both the V_{CC} and V_L supply rails are configurable from 1.5 V to 5.5 V. This allows voltage logic signals on the V_L side to be translated into lower, higher or equal value voltage logic signals on the V_{CC} side, and vice-versa.

The NLSX4402 translator has internal pull-up resistors on the I/O lines. The pull-up resistors are used to pull up the I/O lines to either V_L or V_{CC} . The NLSX4402 is an excellent match for open-drain applications such as the I²C communication bus.

Features

- $\bullet~V_L$ can be Less than, Greater than or Equal to V_{CC}
- Wide V_{CC} Operating Range: 1.5 V to 5.5 V
 Wide V_L Operating Range: 1.5 V to 5.5 V
- Enable Input and I/O Pins are Overvoltage Tolerant (OVT) to 5.5 V
- Non-preferential Powerup Sequencing
- Power-Off Protection
- Small Space Saving Packages: 1.45 mm x 1.0 mm UDFN8
 1.8 mm x 1.2 mm X2DFN8
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

Typical Applications

- I²C, SMBus
- Low Voltage ASIC Level Translation
- Mobile Phones, PDAs, Cameras

Important Information

- ESD Protection for All Pins
 - Human Body Model (HBM) > 5000 V



ON Semiconductor®

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MARKING DIAGRAMS



UDFN8 1.45 x 1.0 CASE 517BZ



J = Specific Device Code M = Date Code



X2DFN8 1.8 x 1.2 CASE 716AC

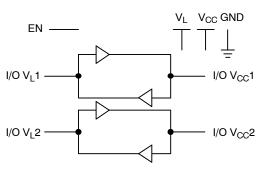


AA = Specific Device Code
M = Date Code

■ Pb-Free Package

(Note: Microdot may be in either location)

LOGIC DIAGRAM



ORDERING INFORMATION

Device	Package	Shipping [†]
NLSX4402FMUTCG	UDFN8 (Pb-Free)	3000 / Tape & Reel
NLSX4402MX2ATAG (In Development)	X2DFN8 (Pb-Free)	3000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

This document contains information on some products that are still under development. ON Semiconductor reserves the right to change or discontinue these products without notice.

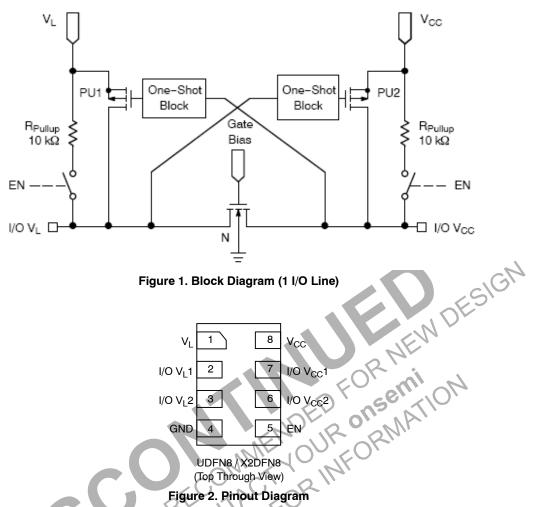
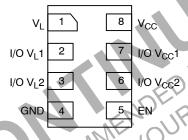


Figure 1. Block Diagram (1 I/O Line)



UDFN8 / X2DFN8 (Top Through View)

Figure 2. Pinout Diagram

PIN ASSIGNMENT

Pins	Description
V _{CC}	V _{CC} Supply Voltage
V _L	V _L Supply Voltage
GND	Ground
EN	Output Enable, Referenced to V _L
I/O V _{CC} n	I/O Port, Referenced to V _{CC}
I/O V _L n	I/O Port, Referenced to V _L

FUNCTION TABLE

EN	Operating Mode
L	Hi–Z
Н	I/O Buses Connected

MAXIMUM RATINGS

Symbol	Parameter	Value	Condition	Unit
V _{CC}	High-side DC Supply Voltage	-0.5 to +7.0		V
V _L	High-side DC Supply Voltage	-0.5 to +7.0		V
I/O V _{CC}	V _{CC} -Referenced DC Input/Output Voltage	-0.5 to +7.0		V
I/O V _L	V _L -Referenced DC Input/Output Voltage	-0.5 to +7.0		V
V _{EN}	Enable Control Pin DC Input Voltage	-0.5 to +7.0		V
I _{I/O_SC}	Short-Circuit Duration (I/O V _L and I/O V _{CC} to GND)	±50	Continuous	mA
I _{I/OK}	Input/Output Clamping Current (I/O VL and I/O VCC)	-50	V _{I/O} < 0	mA
T _{STG}	Storage Temperature	-65 to +150		°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter	Min	Max	Unit
V _{CC}	High-side Positive DC Supply Voltage	1.5	5.5	V
V_L	High-side Positive DC Supply Voltage	1.5	5.5	V
V _{EN}	Enable Control Pin Voltage	GND	5.5	V
V _{IO_VCC}	I/O Pin Voltage (Side referred to V _{CC})	GND	5.5	V
V _{IO_VL}	I/O Pin Voltage (Side referred to V _L)	GND	5.5	V
Δt/ΔV	Input Transition Rise and Fall Rate A- or B-Ports, Push-Pull Driving Control Input	MATI	10 10	ns/V
T _A	Operating Temperature Range	-40	+85	°C
	Operating Temperature Range eration above the stresses listed in the Recommended Operating Ranges is not implied. Be ad Operating Ranges limits may affect device reliability.			

DC ELECTRICAL CHARACTERISTICS ($V_L = 1.5 \text{ V}$ to 5.5 V and $V_{CC} = 1.5 \text{ V}$ to 5.5 V, unless otherwise specified) (Note 1)

			-4	10°C to +85°	°C	
Symbol	Parameter	Test Conditions (Note 2)	Min	Тур	Max	Unit
V _{IHC}	I/O V _{CC} Input HIGH Voltage		V _{CC} - 0.4	-	-	V
V _{ILC}	I/O V _{CC} Input LOW Voltage		-	-	0.15	V
V _{IHL}	I/O VL Input HIGH Voltage		V _L – 0.4	-	-	V
V _{ILL}	I/O VL Input LOW Voltage		-	-	0.15	V
V _{IH}	Control Pin Input HIGH Voltage		0.65 * V _L	-	-	V
V _{IL}	Control Pin Input LOW Voltage		-	-	0.35 * V _L	٧
V _{OHC}	I/O Vcc Output HIGH Voltage	I/O V _{CC} source current = 20 μA	2/3 * V _{CC}	-	-	٧
V _{OLC}	I/O Vcc Output LOW Voltage	I/O V _{CC} sink current = 1 mA	-	-	0.4	٧
V _{OHL}	I/O V∟Output HIGH Voltage	I/O V _L source current = 20 μA	2/3 * V _L	-	-	٧
V _{OLL}	I/O V₋Output LOW Voltage	I/O V _L sink current = 1 mA		-	0.4	٧
I _{QVCC}	V _{CC} Supply Current	I/O V_{CC} and I/O V_L unconnected, $V_{EN} = V_L$ $V_L = 5.5 \text{ V}, V_{CC} = 0 \text{ V}$		0.5	2.0 1.0	μΑ
	Supply Current	$V_{L} = 0.3 \text{ V}, V_{CC} = 0 \text{ V}$ $V_{L} = 0 \text{ V}, V_{CC} = 5.5 \text{ V}$	-	OF	-1.0 -1.0	
I _{QVL}	V _∟ Supply Current	I/O V _{CC} and I/O V _L unconnected, V _{EN} = V _L	- /	0.3	1.5	μΑ
	Supply Current	$V_L = 5.5 \text{ V}, V_{CC} = 0 \text{ V}$ $V_L = 0 \text{ V}, V_{CC} = 5.5 \text{ V}$	2 MIL	- -	–1.0 1.0	
I _{TS-VCC}	V _{CC} Tristate Output Mode	I/O V_{CC} and I/O V_L unconnected, $V_{EN} = GND$	-01	0.1	1.0	μΑ
I _{TS-VL}	V _L Tristate Output Mode Supply Current	I/O V_{CC} and I/O V_{L} unconnected, V_{EN} = GND	Sent	(O.1	1.0	μΑ
II	Enable Pin Input Leakage Current	CHUR	SMI	-	1.0	μΑ
l _{OFF}	I/O Power-Off Leakage Current	I/O V _{CC} Port, V _{CC} = 0 V, V _L = 0 to 5.5 V	-	-	1.0	μΑ
		I/O VL Port, VCC = 0 to 5.5 V, V _L = 0 V	-	-	1.0	
l _{OZ}	I/O Tristate Output Mode Leakage Current	RENTREOR	-	0.1	1.0	μΑ
R _{PU}	Pull–Up Resistors I/O V _L and V _C	COLME	-	10	_	kΩ

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

1. Typical values are for $V_L = +1.8 \text{ V}$, $V_{CC} = +3.3 \text{ V}$ and $T_A = +25^{\circ}\text{C}$.

2. All units are production tested at $T_A = +25^{\circ}\text{C}$. Limits over the operating temperature range are guaranteed by design.

TIMING CHARACTERISTICS - RAIL-TO-RAIL DRIVING CONFIGURATIONS

(I/O test circuit of Figures 3 and 4, C_{LOAD} = 15 pF, driver output impedance \leq 50 Ω , R_{LOAD} = 1 M Ω)

				0°C to +85 Notes 3 & 4		
Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
V _L = 1.5 V, V	_{CC} = 1.5 V					
t _{RVCC}	I/O V _{CC} Rise Time			9	32	ns
t _{FVCC}	I/O V _{CC} Fall Time			11	20	ns
t _{RVL}	I/O V _L Rise Time			20	30	ns
t _{FVL}	I/O V _L Fall Time			10	13	ns
t _{PDVL-VCC}	Propagation Delay (Driving I/O V _L , V _L to V _{CC})			7	16	ns
t _{PDVCC-VL}	Propagation Delay (Driving I/O V _{CC} , V _{CC} to V _L)			12	15	ns
t _{EN}	Enable Time				50	ns
t _{DIS}	Disable Time				300	ns
t _{PPSKEW}	Part-to-Part Skew			1.5	2	ns
MDR	Maximum Data Rate		15	106		Mbps
V _L = 1.5 V, V	_{CC} = 5.5 V			1/1		
t _{RVCC}	I/O V _{CC} Rise Time		Nr	9	12	ns
t _{FVCC}	I/O V _{CC} Fall Time	10/	in	17	30	ns
t _{RVL}	I/O V _L Rise Time	10	6/1	(2)	4	ns
t _{FVL}	I/O V _L Fall Time	JOE ON	An.	3	7	ns
t _{PDVL-VCC}	Propagation Delay (Driving I/O V _L , V _L to V _{CC})	MILLE	514.	14	24	ns
t _{PDVCC-VL}	Propagation Delay (Driving I/O V _{CC} , V _{CC} to V _L)	10,160		3	5	ns
t _{EN}	Enable Time	1011			40	ns
t _{DIS}	Disable Time	20/			250	ns
t _{PPSKEW}	Part-to-Part Skew	, ,			2	ns
MDR	Maximum Data Rate		20			Mbps
V _L = 1.8 V, V	CC = 2.8 V					
t _{RVCC}	I/O V _{CC} Rise Time			11	18	ns
t _{FVCC}	I/O V _{CC} Fall Time			10	15	ns
t _{RVL}	I/O V _L Rise Time			12	15	ns
t _{FVL}	I/O V _L Fall Time			5	8	ns
t _{PDVL-VCC}	Propagation Delay (Driving I/O V _L , V _L to V _{CC})			7	10	ns
t _{PDVCC-VL}	Propagation Delay (Driving I/O V _{CC} , V _{CC} to V _L)			5	9	ns
t _{EN}	Enable Time				50	ns
t _{DIS}	Disable Time				300	ns
t _{PPSKEW}	Part-to-Part Skew				2	ns
MDR	Maximum Data Rate		20			Mbps
V _L = 2.5 V, V	/ _{CC} = 3.6 V					
t _{RVCC}	I/O V _{CC} Rise Time			8	12	ns

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

- 3. Typical values are for the specified V_L and V_{CC} at $T_A = +25^{\circ}C$. All units are production tested at $T_A = +25^{\circ}C$. 4. Limits over the operating temperature range are guaranteed by design.
- 5. Skew is the variation of propagation delay between output signals and applies only to output signals on the same port (I/O VLn or I/O VCCn) and switching with the same polarity (LOW-to-HIGH or HIGH-to-LOW). Skew is defined by applying a single input to the two input channels and measuring the difference in propagation delays between the output channels.

TIMING CHARACTERISTICS - RAIL-TO-RAIL DRIVING CONFIGURATIONS (continued)

(I/O test circuit of Figures 3 and 4, C_{LOAD} = 15 pF, driver output impedance \leq 50 Ω , R_{LOAD} = 1 M Ω)

				0°C to +85 Notes 3 & 4		
Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
V _L = 2.5 V, V	_{CC} = 3.6 V		·			
t _{FVCC}	I/O V _{CC} Fall Time			8	12	ns
t _{RVL}	I/O V _L Rise Time			7	10	ns
t _{FVL}	I/O V _L Fall Time			5	7	ns
t _{PDVL-VCC}	Propagation Delay (Driving I/O V _L , V _L to V _{CC})			7	10	ns
t _{PDVCC-VL}	Propagation Delay (Driving I/O V _{CC} , V _{CC} to V _L)			5	8	ns
t _{EN}	Enable Time				40	ns
t _{DIS}	Disable Time				225	ns
t _{PPSKEW}	Part-to-Part Skew				2	ns
MDR	Maximum Data Rate		24		3/0	Mbps
V _L = 2.8 V, V	_{CC} = 1.8 V			106		
t _{RVCC}	I/O V _{CC} Rise Time			13	20	ns
t _{FVCC}	I/O V _{CC} Fall Time		Mr	7	10	ns
t _{RVL}	I/O V _L Rise Time	201	in	8	13	ns
t _{FVL}	I/O V _L Fall Time	10	6/1	9	15	ns
t _{PDVL-VCC}	Propagation Delay (Driving I/O V _L , V _L to V _{CC})	UK ON	· NA	6	9	ns
t _{PDVCC-VL}	Propagation Delay (Driving I/O V _{CC} , V _{CC} to V _L)	WALLEY OF	5/1/11	7	12	ns
t _{EN}	Enable Time	10,160			60	ns
t _{DIS}	Disable Time	10114			250	ns
t _{PPSKEW}	Part-to-Part Skew	201			2	ns
MDR	Maximum Data Rate		24			Mbps
V _L = 3.6 V, V	cc = 2.5 V					
t _{RVCC}	I/O V _{CC} Rise Time			9	12	ns
t _{FVCC}	I/O V _{CC} Fall Time			6	9	ns
t _{RVL}	I/O V _L Rise Time			6	12	ns
$t_{\sf FVL}$	I/O V _L Fall Time			7	12	ns
t _{PDVL-VCC}	Propagation Delay (Driving I/O V_L , V_L to V_{CC})			5	7	ns
t _{PDVCC-VL}	Propagation Delay (Driving I/O V _{CC} , V _{CC} to V _L)			6	9	ns
t _{EN}	Enable Time				50	ns
t _{DIS}	Disable Time				250	ns
t _{PPSKEW}	Part-to-Part Skew				2	ns
MDR	Maximum Data Rate		24			Mbps
V _L = 5.5 V, V	CC = 1.5 V					
t _{RVCC}	I/O V _{CC} Rise Time			13	20	ns
t _{FVCC}	I/O V _{CC} Fall Time			6	9	ns

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

- 3. Typical values are for the specified V_L and V_{CC} at $T_A = +25^{\circ}C$. All units are production tested at $T_A = +25^{\circ}C$. 4. Limits over the operating temperature range are guaranteed by design.
- 5. Skew is the variation of propagation delay between output signals and applies only to output signals on the same port (I/O_VLn or I/O_VCCn) and switching with the same polarity (LOW-to-HIGH or HIGH-to-LOW). Skew is defined by applying a single input to the two input channels and measuring the difference in propagation delays between the output channels.

TIMING CHARACTERISTICS - RAIL-TO-RAIL DRIVING CONFIGURATIONS (continued)

(I/O test circuit of Figures 3 and 4, C_{LOAD} = 15 pF, driver output impedance \leq 50 Ω , R_{LOAD} = 1 M Ω)

			-40°C to +8 (Notes 3 &			
Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
V _L = 5.5 V, V	/ _{CC} = 1.5 V					
t _{RVL}	I/O V _L Rise Time			8	10	ns
t _{FVL}	I/O V _L Fall Time			20	27	ns
t _{PDVL-VCC}	Propagation Delay (Driving I/O V _L , V _L to V _{CC})			5	8	ns
t _{PDVCC-VL}	Propagation Delay (Driving I/O V _{CC} , V _{CC} to V _L)			14	24	ns
t _{EN}	Enable Time					ns
t _{DIS}	Disable Time					ns
t _{PPSKEW}	Part-to-Part Skew				2	ns
MDR	Maximum Data Rate		20		CN	Mbps
V _L = 5.5 V, V	/ _{CC} = 5.5 V				3/0	
t _{RVCC}	I/O V _{CC} Rise Time			5	7	ns
t _{FVCC}	I/O V _{CC} Fall Time			6	8	ns
t _{RVL}	I/O V _L Rise Time		Mr	5	7	ns
t _{FVL}	I/O V _L Fall Time	10,	in	4	7	ns
t _{PDVL-VCC}	Propagation Delay (Driving I/O V _L , V _L to V _{CC})	101	6/1	(4)	6	ns
t _{PDVCC-VL}	Propagation Delay (Driving I/O V _{CC} , V _{CC} to V _L)	105,000	· NA	4	6	ns
t _{EN}	Enable Time	WALL OF	5/1/1.		30	ns
t _{DIS}	Disable Time	10,160			225	ns
t _{PPSKEW}	Part-to-Part Skew	1 5 114.			2	ns
MDR	Maximum Data Rate	ZOT	24			Mbps

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

3. Typical values are for the specified V_L and V_{CC} at $T_A = +25^{\circ}C$. All units are production tested at $T_A = +25^{\circ}C$.

4. Limits over the operating temperature range are guaranteed by design.

- 5. Skew is the variation of propagation delay between output signals and applies only to output signals on the same port (I/O VLn or I/O VCCn) and switching with the same polarity (LOW-to-HIGH or HIGH-to-LOW). Skew is defined by applying a single input to the two input channels and measuring the difference in propagation delays between the output channels.

TIMING CHARACTERISTICS - OPEN DRAIN DRIVING CONFIGURATIONS

(I/O test circuit of Figures 5 and 6, C_{LOAD} = 15 pF, driver output impedance \leq 50 Ω , R_{LOAD} = 1 M Ω)

*			-40°C to +85°C (Notes 6 & 7)				
Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit	
V _L = 1.5 V, \	/ _{CC} = 1.5 V						
t _{RVCC}	I/O V _{CC} Rise Time			55	70	ns	
t _{FVCC}	I/O V _{CC} Fall Time			7	14	ns	
t _{RVL}	I/O V _L Rise Time			50	65	ns	
t _{FVL}	I/O V _L Fall Time			7	12	ns	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

- 6. Typical values are for the specified V_L and V_{CC} at T_A = +25°C. All units are production tested at T_A = +25°C.
- Limits over the operating temperature range are guaranteed by design.
- 8. Skew is the variation of propagation delay between output signals and applies only to output signals on the same port (I/O_VLn or I/O_VCCn) and switching with the same polarity (LOW-to-HIGH or HIGH-to-LOW). Skew is defined by applying a single input to the two input channels and measuring the difference in propagation delays between the output channels.

TIMING CHARACTERISTICS - OPEN DRAIN DRIVING CONFIGURATIONS (continued)

(I/O test circuit of Figures 5 and 6, C_{LOAD} = 15 pF, driver output impedance \leq 50 Ω , R_{LOAD} = 1 M Ω)

			-40°C to +85°C (Notes 6 & 7)			
Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
V _L = 1.5 V, V	/ _{CC} = 1.5 V					
t _{PDVL-VCC}	Propagation Delay (Driving I/O V _L , V _L to V _{CC})			20	34	ns
t _{PDVCC-VL}	Propagation Delay (Driving I/O V _{CC} , V _{CC} to V _L)			19	34	ns
t _{EN}	Enable Time				100	ns
t _{DIS}	Disable Time				300	ns
t _{PPSKEW}	Part-to-Part Skew				2	ns
MDR	Maximum Data Rate		3			Mbps
V _L = 1.5 V, V	/ _{CC} = 5.5 V	I			_	
t _{RVCC}	I/O V _{CC} Rise Time			22	34	ns
t _{FVCC}	I/O V _{CC} Fall Time			20	27	ns
t _{RVL}	I/O V _L Rise Time			43	55	ns
t _{FVL}	I/O V _L Fall Time			6	12	ns
t _{PDVL-VCC}	Propagation Delay (Driving I/O V _L , V _L to V _{CC})		NF	13	26	ns
t _{PDVCC-VL}	Propagation Delay (Driving I/O V _{CC} , V _{CC} to V _L)		in	19	24	ns
t _{EN}	Enable Time		· GI	10/2	80	ns
t _{DIS}	Disable Time	JOE OF	An.		250	ns
t _{PPSKEW}	Part-to-Part Skew	ENTIR	5141.		2	ns
MDR	Maximum Data Rate	10,10,160	3			Mbps
V _L = 1.8 V, V	/ _{CC} = 3.3 V	W.C.L.				
t _{RVCC}	I/O V _{CC} Rise Time	(PCO)		34	40	ns
t _{FVCC}	I/O V _{CC} Fall Time	TE.		1	15	ns
t _{RVL}	I/O V _L Rise Time	//		40	48	ns
t_{FVL}	I/O V _L Fall Time			1	2	ns
t _{PDVL-VCC}	Propagation Delay (Driving I/O V _L , V _L to V _{CC})			9	15	ns
t _{PDVCC-VL}	Propagation Delay (Driving I/O V _{CC} , V _{CC} to V _L)			6	11	ns
t _{EN}	Enable Time				70	ns
t _{DIS}	Disable Time				300	ns
t _{PPSKEW}	Part-to-Part Skew				2	ns
MDR	Maximum Data Rate		7			Mbps
V _L = 5.5 V, V	/ _{CC} = 1.5 V				•	
t _{RVCC}	I/O V _{CC} Rise Time			44	52	ns
t _{FVCC}	I/O V _{CC} Fall Time			1	2	ns
t _{RVL}	I/O V _L Rise Time			7	30	ns
t _{FVL}	I/O V _L Fall Time			17	23	ns
t _{PDVL-VCC}	Propagation Delay (Driving I/O V _L , V _L to V _{CC})			10	17	ns

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

- 6. Typical values are for the specified V_L and V_{CC} at $T_A = +25^{\circ}C$. All units are production tested at $T_A = +25^{\circ}C$. 7. Limits over the operating temperature range are guaranteed by design.
- 8. Skew is the variation of propagation delay between output signals and applies only to output signals on the same port (I/O VLn or I/O VCCn) and switching with the same polarity (LOW-to-HIGH or HIGH-to-LOW). Skew is defined by applying a single input to the two input channels and measuring the difference in propagation delays between the output channels.

TIMING CHARACTERISTICS - OPEN DRAIN DRIVING CONFIGURATIONS (continued)

(I/O test circuit of Figures 5 and 6, C_{LOAD} = 15 pF, driver output impedance \leq 50 Ω , R_{LOAD} = 1 M Ω)

	Parameter		-40°C to +85°C (Notes 6 & 7)			
Symbol		Test Conditions	Min	Тур	Max	Unit
V _L = 5.5 V, V	/ _{CC} = 1.5 V					
t _{PDVCC-VL}	Propagation Delay (Driving I/O V _{CC} , V _{CC} to V _L)			12	24	ns
t _{EN}	Enable Time				100	ns
t _{DIS}	Disable Time				300	ns
t _{PPSKEW}	Part-to-Part Skew				2	ns
MDR	Maximum Data Rate		3			Mbps
V _L = 5.5 V, V	_{CC} = 5.5 V					
t _{RVCC}	I/O V _{CC} Rise Time			42	50	ns
t _{FVCC}	I/O V _{CC} Fall Time			2	3	ns
t _{RVL}	I/O V _L Rise Time			44	48	ns
t _{FVL}	I/O V _L Fall Time			2	3	ns
t _{PDVL-VCC}	Propagation Delay (Driving I/O V _L , V _L to V _{CC})			4	6	ns
t _{PDVCC-VL}	Propagation Delay (Driving I/O V _{CC} , V _{CC} to V _L)		Nr	6	9	ns
t _{EN}	Enable Time	-11 CO	in	4	60	ns
t _{DIS}	Disable Time	10	.el	10/	225	ns
t _{PPSKEW}	Part-to-Part Skew	I OF ON	AA.		2	ns
MDR	Maximum Data Rate	CHILL	5/14			Mbps

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

6. Typical values are for the specified V_L and V_{CC} at $T_A = +25^{\circ}C$. All units are production tested at $T_A = +25^{\circ}C$. 7. Limits over the operating temperature range are guaranteed by design.

Limits over the operating temperature range are guaranteed by design.
 Skew is the variation of propagation delay between output signals and applies only to output signals on the same port (I/O_VLn or I/O_VCCn) and switching with the same polarity (LOW-to-HIGH or HIGH-to-LOW). Skew is defined by applying a single input to the two input channels and measuring the difference in propagation delays between the output channels.

TEST SETUP

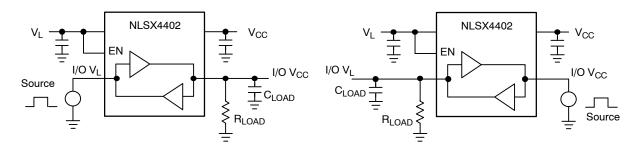


Figure 3. Rail–to–Rail Driving I/O $V_L, \\ V_L$ to V_{CC}

Figure 4. Rail-to-Rail Driving I/O V_{CC} , V_{CC} to V_{L}

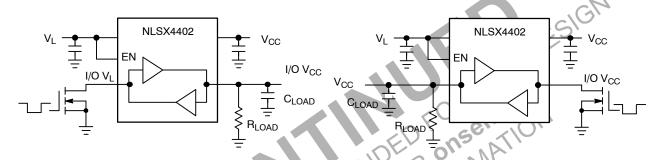


Figure 5. Open–Drain Driving I/O V_L , V_L to V_{CC}

Figure 6. Open-Drain Driving I/O V_{CC}, V_{CC} to V_L

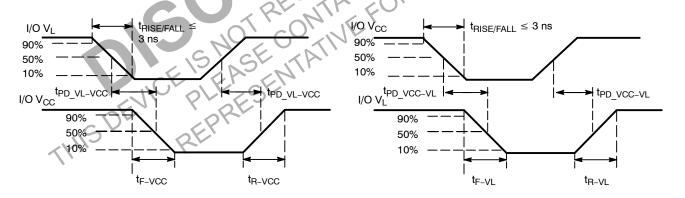
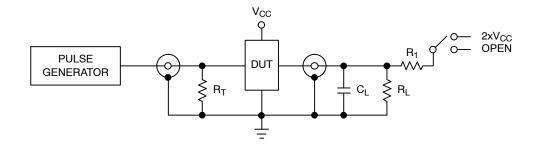


Figure 7. Definition of Timing Specification Parameters

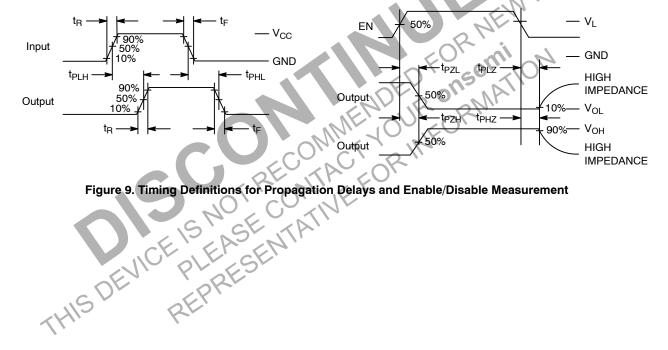


Test	Switch	
t _{PZH} , t _{PHZ}	Open	
t _{PZL} , t _{PLZ}	2 x V _{CC}	

 C_L = 15 pF or equivalent (Includes jig and probe capacitance) R_L = R_1 = 50 k Ω or equivalent

 $R_T = Z_{OUT}$ of pulse generator (typically 50 Ω)

Figure 8. Test Circuit for Enable/Disable Time Measurement



APPLICATIONS INFORMATION

Level Translator Architecture

The NLSX4402 auto sense translator provides bi–directional voltage level shifting to transfer data in multiple supply voltage systems. This device has two supply voltages, V_L and V_{CC} , which set the logic levels on the input and output sides of the translator. When used to transfer data from the V_L to the V_{CC} ports, input signals referenced to the V_L supply are translated to output signals with a logic level matched to V_{CC} . In a similar manner, the V_{CC} to V_L translation shifts input signals with a logic level compatible to V_{CC} to an output signal matched to V_L .

The NLSX4402 consists of two bi-directional channels that independently determine the direction of the data flow without requiring a directional pin. The one-shot circuits are used to detect the rising or falling input signals. In addition, the one shots decrease the rise and fall time of the output signal for high-to-low and low-to-high transitions.

Each input/output channel has an internal 10 k Ω pull. The magnitude of the pullup resistors can be reduced by connecting external resistors in parallel to the internal 10 k Ω resistors.

Input Driver Requirements

The rise (t_R) and fall (t_F) timing parameters of the open drain outputs depend on the magnitude of the pull-up resistors. In addition, the propagation times (t_{PD}), skew (t_{PSKEW}) and maximum data rate depend on the impedance of the device that is connected to the translator. The timing

parameters listed in the data sheet assume that the output impedance of the drivers connected to the translator is less than 50 k Ω .

Enable Input (EN)

The NLSX4402 has an Enable pin (EN) that provides tri–state operation at the I/O pins. Driving the Enable pin to a low logic level minimizes the power consumption of the device and drives the I/O $V_{\rm CC}$ and I/O $V_{\rm L}$ pins to a high impedance state. Normal translation operation occurs when the EN pin is equal to a logic high signal. The EN pin is referenced to the $V_{\rm L}$ supply and has Overvoltage Tolerant (OVT) protection.

Power Supply Guidelines

During normal operation, supply voltage V_L can be greater than, less than or equal to $V_{\rm CC}$. The sequencing of the power supplies will not damage the device during the power up operation.

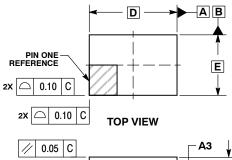
For optimal performance, 0.01 μF to 0.1 μF decoupling capacitors should be used on the V_L and V_{CC} power supply pins. Ceramic capacitors are a good design choice to filter and bypass any noise signals on the voltage lines to the ground plane of the PCB. The noise immunity will be maximized by placing the capacitors as close as possible to the supply and ground pins, along with minimizing the PCB connection traces.

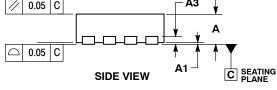


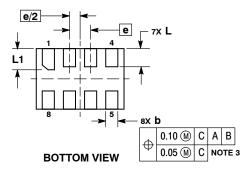


UDFN8, 1.45x1.00, 0.35P CASE 517BZ ISSUE O

DATE 18 MAY 2011







GENERIC MARKING DIAGRAM*



X = Specific Device Code

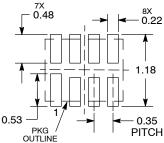
M = Date Code

NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- CONTROLLING DIMENSION: MILLIMETERS. DIMENSION & APPLIES TO PLATED TERMINAL AND IS MEASURED BETWEEN
- 0.15 AND 0.20 MM FROM TERMINAL TIP. PACKAGE DIMENSIONS EXCLUSIVE OF BURRS AND MOLD FLASH.

	MILLIMETERS		
DIM	MIN	MAX	
Α	0.45	0.55	
A1	0.00	0.05	
A3	0.13 REF		
b	0.15	0.25	
D	1.45 BSC		
E	1.00 BSC		
е	0.35 BSC		
L	0.25	0.35	
L1	0.30	0.40	

RECOMMENDED SOLDERING FOOTPRINT*



DIMENSIONS: MILLIMETERS

*For additional information on our Pb-Free strategy and soldering details, please download the onsemi Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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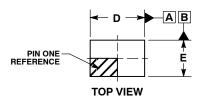
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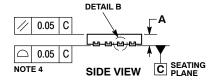
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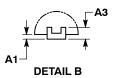


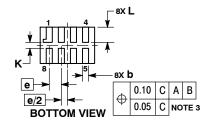
X2DFN8 1.8x1.2, 0.4P CASE 716AC **ISSUE B**

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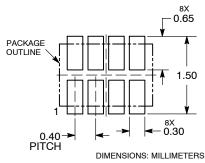








RECOMMENDED SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994. 2. CONTROLLING DIMENSION: MILLIMETERS. 3. DIMENSION b APPLIES TO PLATED
- TERMINAL AND IS MEASURED BETWEEN
- 0.15 AND 0.30 mm FROM THE TERMINAL TIP.
 COPLANARITY APPLIES TO THE EXPOSED
 PAD AS WELL AS THE TERMINALS.

	MILLIMETERS		
DIM	MIN	NOM	MAX
Α	0.34	0.37	0.40
A1		-	0.05
A3	0.127 REF		
b	0.15	0.20	0.25
D	1.75	1.80	1.85
Е	1.15	1.20	1.25
е	0.40 BSC		
K	0.20 REF		
L	0.45	0.50	0.55

GENERIC MARKING DIAGRAM*



XXX = Specific Device Code

= Date Code

= Pb-Free Package

(Note: Microdot may be in either location)

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " ■", may or may not be present. Some products may not follow the Generic Marking.

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